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Nota di bibliografia	Includes bibliographical references.
Nota di contenuto	Introduction -- Cache Architecture and Main Blocks -- Embedded Memory Hierarchy -- SRAM Memory Operation and Yield -- Low Power and High Yield SRAM Memory -- Leakage Reduction -- Embedded Memory Verification -- Embedded Memory Design Validation and Design For Test -- Emerging Memory Technology Opportunities and Challenges.
Sommario/riassunto	This book describes the various tradeoffs systems designers face when designing embedded memory. Readers designing multi-core systems and systems on chip will benefit from the discussion of different topics from memory architecture, array organization, circuit design techniques and design for test. The presentation enables a multi-disciplinary approach to chip design, which bridges the gap between the architecture level and circuit level, in order to address yield, reliability and power-related issues for embedded memory. · Provides a comprehensive overview of embedded memory design and associated challenges and choices; · Explains tradeoffs and dependencies across different disciplines involved with multi-core and system on chip memory design; · Includes detailed discussion of memory hierarchy and its impact on energy and

performance; · Uses real product examples to demonstrate embedded memory design flow from architecture, to circuit design, design for test and yield analysis.

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